Approved For Release 2006/09/21 : CIA-RDP78B04770A001500070020-8	STAT
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January 14, 1964 /	
re: Measuring Techniques.	STAT
Bob, when I was in your crice last December we dis	<u> </u>
cussed briefly some measuring techniques. You mentioned you had received a proposal to use some mechanical property of quartz for submicron measurement of distance, I think it was. We didn't really have a chance to finish our conversation and I can't	
recall the details. As I remember, it sounded as though it might have some problems associated with obtaining glass of sufficient uniformity, but whe idea was perhaps promising enough to look into.	
While your thinking about that, you might consider another possibility. has proposed a device to, I think, to develop a device to make sub-	STAT STAT
micron measurements. They plan to use a light beam of a Laser and since it is coherent they can count light waves. They didn't go into details, but they think they can get a least count of 0.15 microns.	
I'm sure would give you the details if you asked him, and I think you should consider it.	STAT
On the other hand, since is already well into a program to measure with a least count of 0.25 microns, is it worth while investing in	STAT
other investigative work?	STAT
enly be under taken only if it shows promise of being considerably cheaper in its application to production	
machines and also retains the two significant features of the system: I i.e.non-ambiguity of count and no limitation of the traverse velocity.	STAT
These are some thoughts I had on the subject. I can't answer the question I posed above, but I would be glad to discuss it with you next time we get	er e
together.	STAT STAT
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[DDR-Dupe]	